

Search Notes**Application/Control No.**

10/679,290

Examiner

ALEX LIEW

**Applicant(s)/Patent under
Reexamination**

SHISHIDO ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/141-152,154 limited to text search	3/7/2007	AL
382/141-152,154 limited to text search	9/13/2007	AL
382/141-152,154 limited to text search	3/12/2008	AL